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<u>set Nam</u>	<u>e Query</u>	Hit Count	<u>Set Name</u>		
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DB=P	GPB, USPT, USOC, EPAB, JPAB, DWPI, TDBD; PLUR=YES; OP=A	4DJ			
<u>L17</u>	16 and L16	. 8	<u>L17</u>		
<u>L16</u>	112 and L15	169	<u>L16</u>		
<u>L15</u>	18 and L14	5633	<u>L15</u>		
<u>L14</u>	degree\$ near3 value\$	49498	<u>L14</u>		
<u>L13</u>	17 and L12	15	<u>L13</u>		
<u>L12</u>	707/\$.ccls.	34700	<u>L12</u>		
<u>L11</u>	19 or L10	26	<u>L11</u>		
<u>L10</u>	L7 and (personal near3 information)	9	<u>L10</u>		
<u>L9</u>	17 and L8	17	<u>L9</u>		
<u>L8</u>	(met or meet or satisf\$) near3 (condition\$ or criteria or criterion)	262827	<u>L8</u>		
<u>L7</u>	14 and L6	100	<u>L7</u>		
<u>L6</u>	(search\$ or quer\$ or retriev\$) near5 (target near3 information)	1870	<u>L6</u>		
<u>L5</u>	(search\$ or quer\$ or retriev\$) near5 (target near3 infromation)	0	<u>L5</u>		
<u>L4</u>	L3 and (search\$ or quer\$ or retriev\$)	44354	<u>L4</u>		
<u>L3</u>	(control near5 (keyword\$ or term\$ or parameter\$))	169549	<u>L3</u>		
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## **Refine Search**

## Search Results -

Terms	Documents	
L7 and L12	15	

Database: EPO A

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Search:

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<u>L12</u>	707/\$.ccls.	34700	<u>L12</u>	
<u>L11</u>	19 or L10	26	<u>L11</u>	
<u>L10</u>	L7 and (personal near3 information)	9	<u>L10</u>	
<u>L9</u>	17 and L8	17	<u>L9</u>	
<u>L8</u>	(met or meet or satisf\$) near3 (condition\$ or criteria or criterion)	262827	<u>L8</u>	
<u>L7</u>	l4 and L6	100	<u>L7</u>	
<u>L6</u>	(search\$ or quer\$ or retriev\$) near5 (target near3 information)	1870	<u>L6</u>	
<u>L5</u>	(search\$ or quer\$ or retriev\$) near5 (target near3 infromation)	0	<u>L5</u>	
<u>L4</u>	L3 and (search\$ or quer\$ or retriev\$)	44354	<u>L4</u>	
<u>L3</u>	(control near5 (keyword\$ or term\$ or parameter\$))	169549	<u>L3</u>	
DB=USPT; PLUR=YES; OP=ADJ				
<u>L2</u>	(5873080 or 6230204 or 5850433 or 5946678).pn.	4	<u>L2</u>	
<u>L1</u>	(5873080 or 6230204 or 5850433).pn.	3	<u>L1</u>	

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